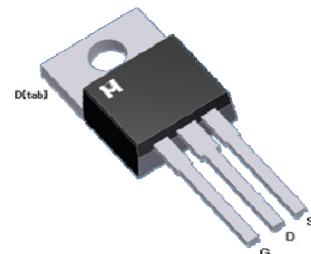
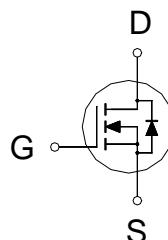


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	900V
R _{DSON} (MAX.)	4Ω
I _D	3.5A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±30	V
Continuous Drain Current	T _C = 25 °C	I _D	3.5	A
	T _C = 100 °C		2.2	
Pulsed Drain Current ¹		I _{DM}	14	
Avalanche Current		I _{AS}	3	
Avalanche Energy	L = 3mH, I _D =3A, R _G =25Ω	E _{AS}	13.5	mJ
Repetitive Avalanche Energy ²	L = 0.5mH	E _{AR}	2.25	
Power Dissipation	T _C = 25 °C	P _D	83	W
	T _C = 100 °C		44	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	1.5	1.5	°C / W
Junction-to-Ambient	R _{θJA}		75	

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	900			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2	3	4	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 900\text{V}, V_{\text{GS}} = 0\text{V}$			10	μA
		$V_{\text{DS}} = 720\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 1.8\text{A}$		3.2	4	Ω
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 25\text{V}, I_D = 1.8\text{A}$		3.6		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		605		pF
Output Capacitance	C_{oss}			64		
Reverse Transfer Capacitance	C_{rss}			3.3		
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = 450\text{V}, V_{\text{GS}} = 15\text{V}, I_D = 1.8\text{A}$		10.4		nC
Gate-Source Charge ^{1,2}	Q_{gs}			2.6		
Gate-Drain Charge ^{1,2}	Q_{gd}			2.8		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$			10		
Rise Time ^{1,2}	t_r	$V_{\text{DS}} = 400\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 15\text{V}, R_{\text{GS}} = 10\Omega$		9		nS
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			15		
Fall Time ^{1,2}	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S				3.5	A
Pulsed Current ³	I_{SM}				14	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.5	V
Reverse Recovery Time	t_{rr}	$I_F = I_S, dI_F/dt = 100\text{A}/\mu\text{s}$		0.5		nS
Reverse Recovery Charge	Q_{rr}				2	nC

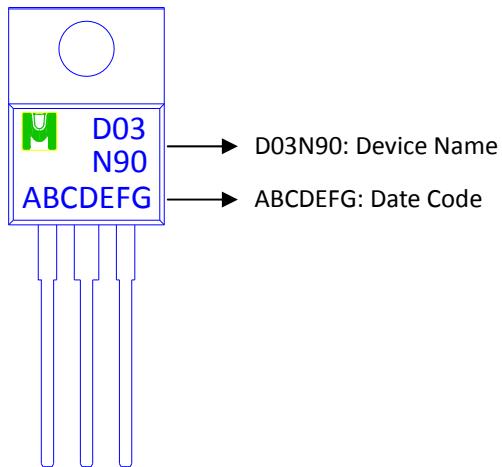
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

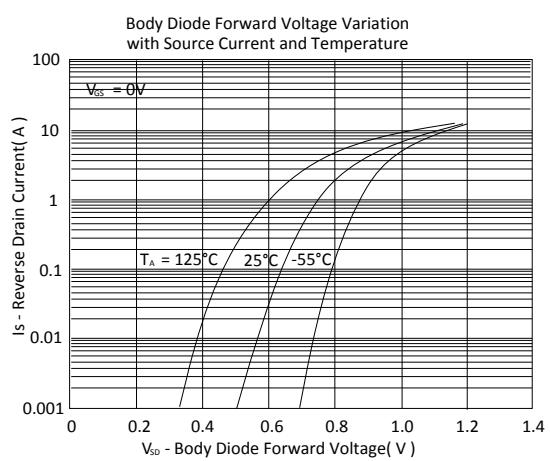
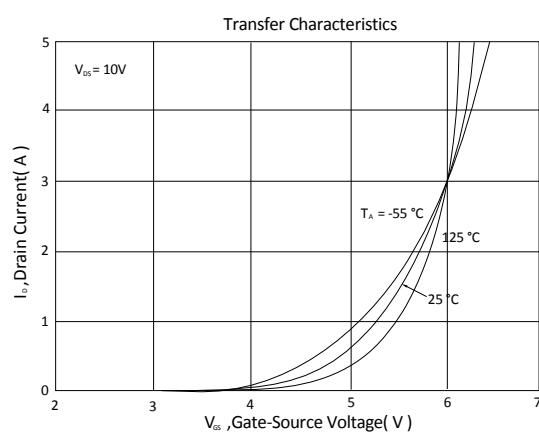
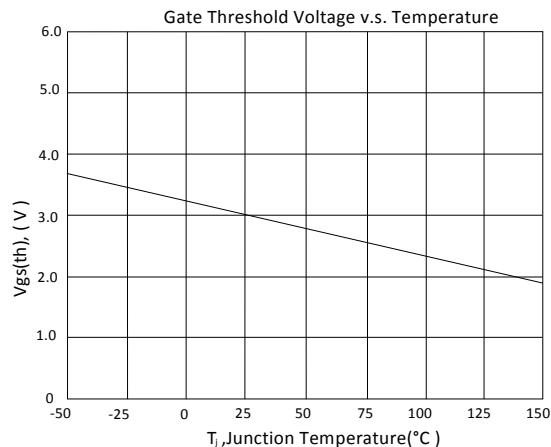
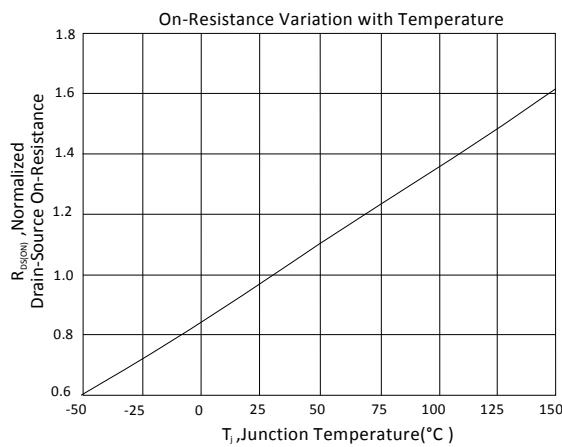
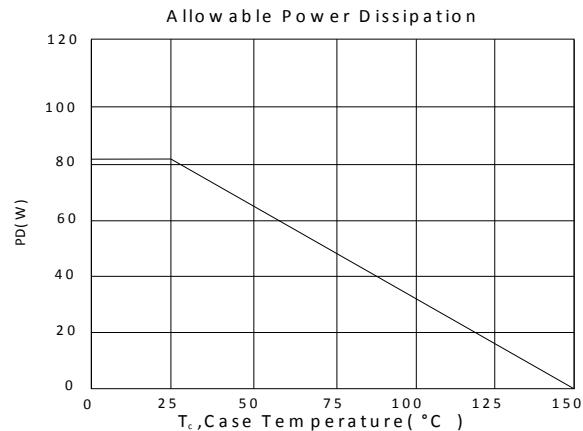
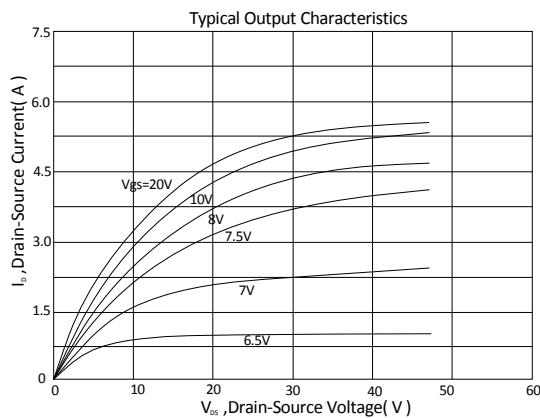
³Pulse width limited by maximum junction temperature.

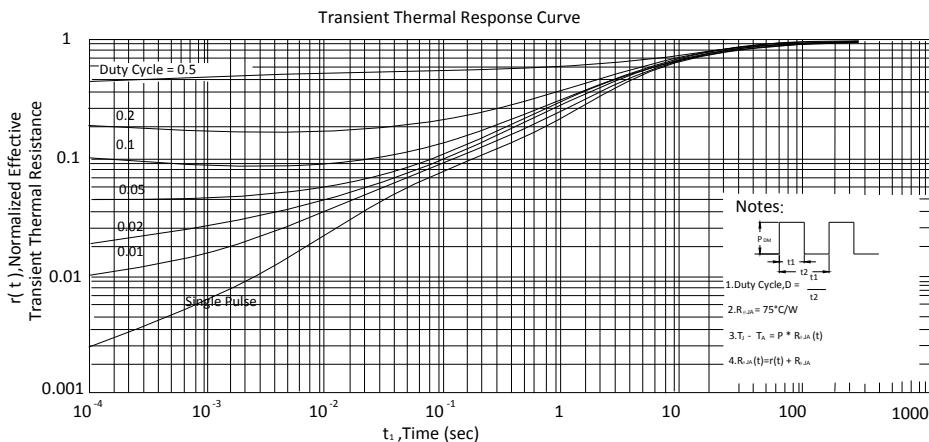
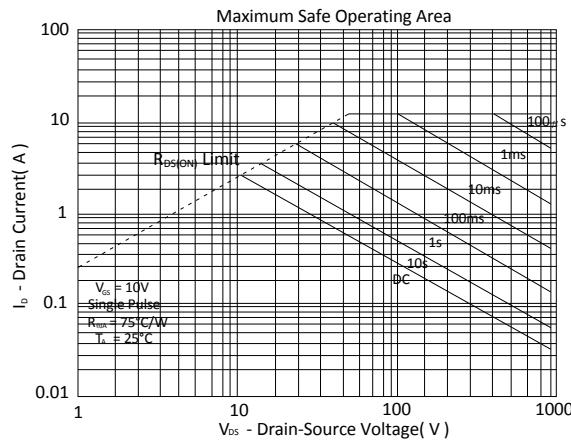
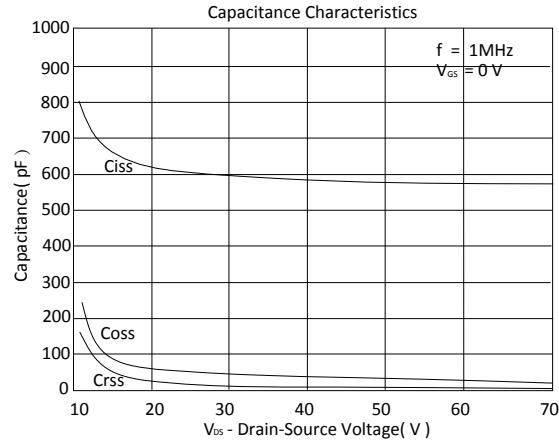
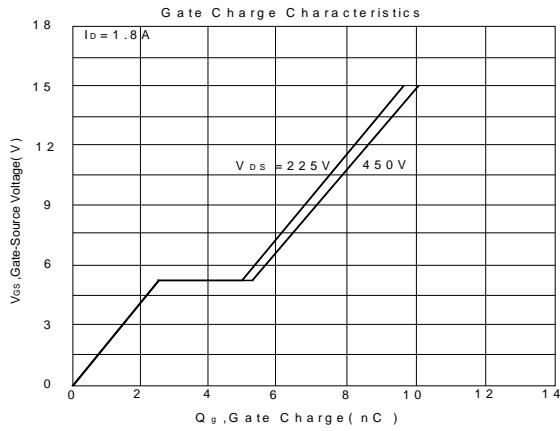
Ordering & Marking Information:

Device Name: EMD03N90E for TO-220E



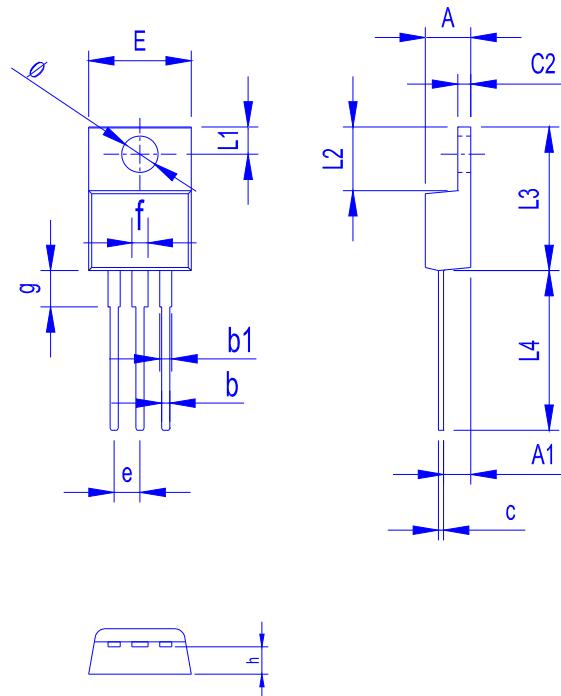
TYPICAL CHARACTERISTICS







Outline Drawing



Dimension in mm

Dimension	A	b	b1	c	c2	E	L1	L2	L3	L4	Ø	e	f	g	h
Min.	4.20	0.70	0.90	0.30	1.10	9.80	2.55	6.10	14.80	13.50	3.40	2.35	1.30	3.40	2.40
Max.	4.80	1.10	1.50	0.70	1.50	10.50	2.85	6.50	15.40	14.50	3.80	2.75	1.90	3.80	3.00